Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from,Europe,America and south Asia,supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of “Quality Parts,Customers Priority,Honest Operation,and Considerate Service”,our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!

Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832
Email & Skype: info@chipsmall.com Web: www.chipsmall.com
Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China

Important notice

Dear Customer,

On 7 February 2017 the former NXP Standard Product business became a new company with the tradename **Nexperia**. Nexperia is an industry leading supplier of Discrete, Logic and PowerMOS semiconductors with its focus on the automotive, industrial, computing, consumer and wearable application markets

In data sheets and application notes which still contain NXP or Philips Semiconductors references, use the references to Nexperia, as shown below.

Instead of http://www.nxp.com, http://www.philips.com/ or http://www.semiconductors.philips.com/, use **http://www.nexperia.com**

Instead of sales.addresses@www.nxp.com or sales.addresses@www.semiconductors.philips.com, use **salesaddresses@nexperia.com** (email)

Replace the copyright notice at the bottom of each page or elsewhere in the document, depending on the version, as shown below:
- © NXP N.V. (year). All rights reserved or © Koninklijke Philips Electronics N.V. (year). All rights reserved
Should be replaced with:
- **© Nexperia B.V. (year). All rights reserved**.

If you have any questions related to the data sheet, please contact our nearest sales office via e-mail or telephone (details via **salesaddresses@nexperia.com**). Thank you for your cooperation and understanding,

Kind regards,

Team Nexperia

74ALVC573

Octal D-type transparent latch; 3-state

Rev. 03 — 26 October 2007 Product data sheet

1. General description

The 74ALVC573 is an octal D-type transparent latch featuring separate D-type inputs for each latch and 3-state true outputs for bus-oriented applications. A latch enable (LE) input and an outputs enable ($\overline{OE}$) input are common to all latches.

When pin LE is HIGH, data at the D-inputs (pins D0 to D7) enters the latches. In this condition, the latches are transparent, that is, a latch output will change each time its corresponding D-input changes. When pin LE is LOW, the latches store the information that was present at the D-inputs one set-up time preceding the HIGH-to-LOW transition of pin LE.

When pin $\overline{OE}$ is LOW, the contents of the eight latches are available at the Q-outputs (pins Q0 to Q7). When pin $\overline{OE}$ is HIGH, the outputs go to the high-impedance OFF-state. Operation of input pin $\overline{OE}$ does not affect the state of the latches.

The 74ALVC573 is functionally identical to the 74ALVC373, but has a different pin arrangement.

2. Features

- Wide supply voltage range from 1.65 V to 3.6 V
- 3.6 V tolerant inputs/outputs
- CMOS low power consumption
- Direct interface with TTL levels (2.7 V to 3.6 V)
- Power-down mode
- Latch-up performance exceeds 250 mA
- Complies with JEDEC standards:
  - JESD8-7 (1.65 V to 1.95 V)
  - JESD8-5 (2.3 V to 2.7 V)
  - JESD8B/JESD36 (2.7 V to 3.6 V)
- ESD protection:
  - HBM JESD22-A114E exceeds 2000 V
  - MM JESD22-A 115-A exceeds 200 V

3. Ordering information

Table 1. Ordering information

Type number	Package			
	Temperature range	Name	Description	Version
74ALVC573D	–40 °C to +85 °C	SO20	plastic small outline package; 20 leads; body width 7.5 mm	SOT163-1
74ALVC573PW	–40 °C to +85 °C	TSSOP20	plastic thin shrink small outline package; 20 leads; body width 4.4 mm	SOT360-1
74ALVC573BQ	–40 °C to +85 °C	DHVQFN20	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body 2.5 × 4.5 × 0.85 mm	SOT764-1

4. Functional diagram

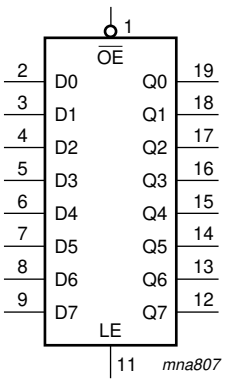


Fig 1. Logic symbol

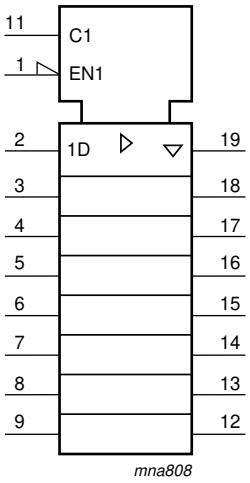


Fig 2. IEC logic symbol

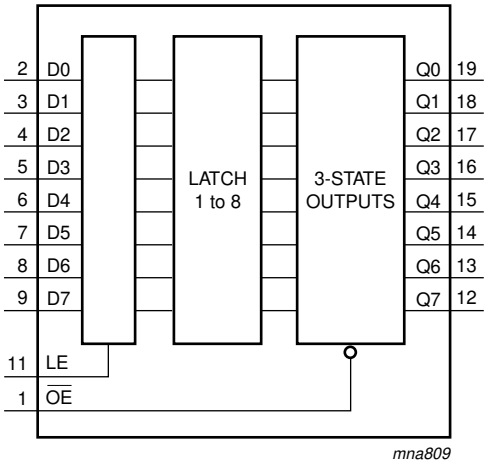


Fig 3. Functional diagram

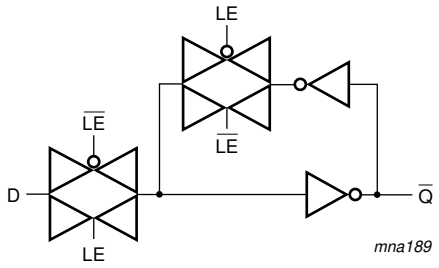


Fig 4. Logic diagram (one latch)

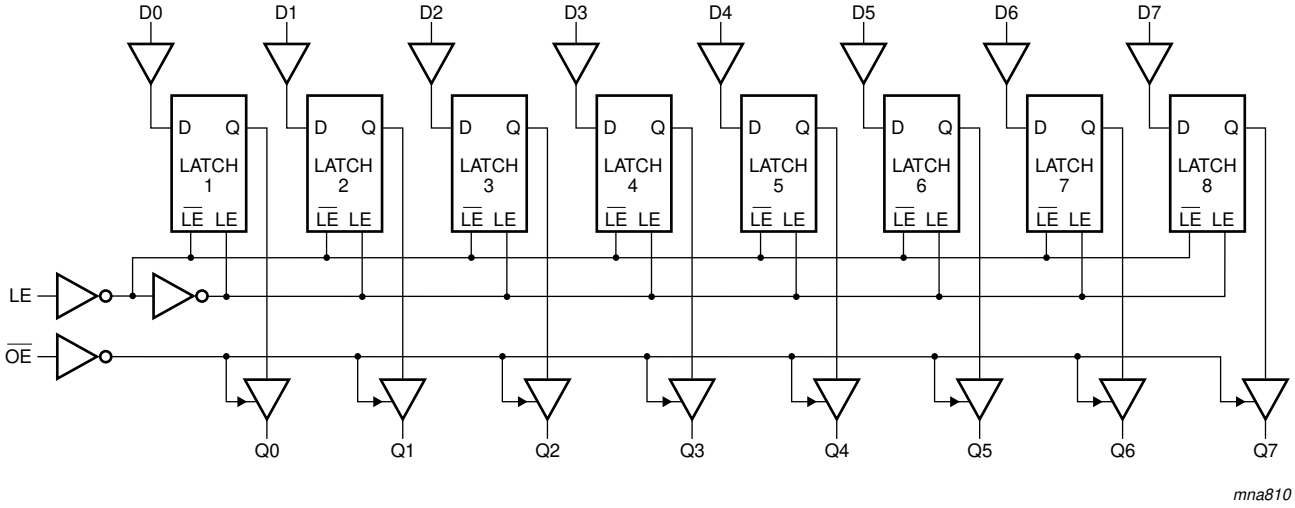


Fig 5. Logic diagram

5. Pinning information

5.1 Pinning

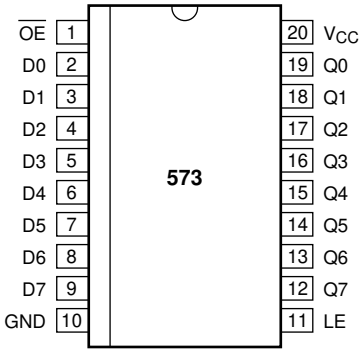
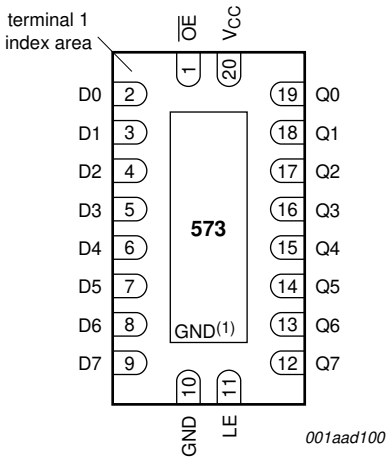


Fig 6. Pin configuration SO20 and TSSOP20



Transparent top view

(1) The die substrate is attached to this pad using conductive die attach material. It can not be used as a supply pin or input.

Fig 7. Pin configuration DHVQFN20

5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
D[0:7]	2, 3, 4, 5, 6, 7, 8, 9	data input
LE	11	latch enable input (active HIGH)
$\overline{OE}$	1	output enable input (active LOW)
Q[0:7]	19, 18, 17, 16, 15, 14, 13, 12	3-state latch output
V_{CC}	20	supply voltage
GND	10	ground (0 V)

6. Functional description

Table 3. Functional table[1]

Operating modes	Input			Internal latch	Output
	$\overline{OE}$	LE	Dn		Qn
Enable and read register (transparent mode)	L	H	L	L	L
	L	H	H	H	H
Latch and read register	L	L	l	L	L
	L	L	h	H	H
Latch register and disable outputs	H	L	l	L	Z
	H	L	h	H	Z

[1] H = HIGH voltage level
h = HIGH voltage level one set-up time prior to the HIGH-to-LOW LE transition
L = LOW voltage level
l = LOW voltage level one set-up time prior to the HIGH-to-LOW LE transition
Z = High-impedance OFF-state

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{CC}	supply voltage			–0.5	+4.6	V
I_{IK}	input clamping current	$V_I < 0$ V		–50	-	mA
V_I	input voltage			–0.5	+4.6	V
I_{OK}	output clamping current	$V_O > V_{CC}$ or $V_O < 0$ V		-	±50	mA
V_O	output voltage	output HIGH or LOW state	[1] [2]	–0.5	V_{CC} + 0.5	V
		output 3-state		–0.5	+4.6	V
		power-down mode, V_{CC} = 0 V	[2]	–0.5	+4.6	V
I_O	output current	V_O = 0 V to V_{CC}		-	±50	mA
I_{CC}	supply current			-	100	mA
I_{GND}	ground current			–100	-	mA
T_{stg}	storage temperature			–65	+150	°C
P_{tot}	total power dissipation	T_{amb} = –40 °C to +85 °C	[3]	-	500	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] When V_{CC} = 0 V (power-down mode), the output voltage can be 3.6 V in normal operation.

[3] For SO20 packages: above 70 °C derate linearly with 8 mW/K.
For TSSOP20 packages: above 60 °C derate linearly with 5.5 mW/K.
For DHVQFN20 packages: above 60 °C derate linearly with 4.5 mW/K.

8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		1.65	3.6	V
V_I	input voltage		0	3.6	V
V_O	output voltage	output HIGH or LOW state	0	V_{CC}	V
		output 3-state	0	3.6	V
		power-down mode; V_{CC} = 0 V	0	3.6	V
T_{amb}	ambient temperature	in free air	−40	+85	°C
$\Delta t/\Delta V$	input transition rise and fall rate	V_{CC} = 1.65 V to 2.7 V	-	20	ns/V
		V_{CC} = 2.7 V to 3.6 V	-	10	ns/V

9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	−40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
V_{IH}	HIGH-level input voltage	V_{CC} = 1.65 V to 1.95 V	0.65 × V_{CC}	-	-	V
		V_{CC} = 2.3 V to 2.7 V	1.7	-	-	V
		V_{CC} = 2.7 V to 3.6 V	2.0	-	-	V
V_{IL}	LOW-level input voltage	V_{CC} = 1.65 V to 1.95 V	-	-	0.35 × V_{CC}	V
		V_{CC} = 2.3 V to 2.7 V	-	-	0.7	V
		V_{CC} = 2.7 V to 3.6 V	-	-	0.8	V
V_{OH}	HIGH-level output voltage	V_I = V_{IH} or V_{IL}				
		I_O = −100 µA; V_{CC} = 1.65 V to 3.6 V	V_{CC} − 0.2	-	-	V
		I_O = −6 mA; V_{CC} = 1.65 V	1.25	-	-	V
		I_O = −12 mA; V_{CC} = 2.3 V	1.8	-	-	V
		I_O = −18 mA; V_{CC} = 2.3 V	1.7	-	-	V
		I_O = −12 mA; V_{CC} = 2.7 V	2.2	-	-	V
		I_O = −18 mA; V_{CC} = 3.0 V	2.4	-	-	V
		I_O = −24 mA; V_{CC} = 3.0 V	2.2	-	-	V
V_{OL}	LOW-level output voltage	V_I = V_{IH} or V_{IL}				
		I_O = 100 µA; V_{CC} = 1.65 V to 3.6 V	-	-	0.2	V
		I_O = 6 mA; V_{CC} = 1.65 V	-	-	0.3	V
		I_O = 12 mA; V_{CC} = 2.3 V	-	-	0.4	V
		I_O = 18 mA; V_{CC} = 2.3 V	-	-	0.6	V
		I_O = 12 mA; V_{CC} = 2.7 V	-	-	0.4	V
		I_O = 18 mA; V_{CC} = 3.0 V	-	-	0.4	V
		I_O = 24 mA; V_{CC} = 3.0 V	-	-	0.55	V
I_I	input leakage current	V_{CC} = 3.6 V; V_I = 3.6 V or GND	-	±0.1	±5	µA

Table 6. Static characteristics *…continued*

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	–40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
I_{OZ}	OFF-state output current	$V_I = V_{IH}$ or V_{IL}; V_{CC} = 1.65 V to 3.6 V; V_O = 3.6 V or GND;	-	±0.1	±10	µA
I_{OFF}	power-off leakage supply	V_{CC} = 0 V; V_I or V_O = 0 V to 3.6 V	-	±0.1	±10	µA
I_{CC}	supply current	V_{CC} = 3.6 V; $V_I = V_{CC}$ or GND; I_O = 0 A	-	0.2	10	µA
ΔI_{CC}	additional supply current	per input pin; V_{CC} = 3.0 V to 3.6 V; $V_I = V_{CC} - 0.6$ V; I_O = 0 A	-	5	750	µA
C_I	input capacitance		-	3.5	-	pF

[1] All typical values are measured at V_{CC} = 3.3 V (unless stated otherwise) and T_{amb} = 25 °C.

10. Dynamic characteristics

Table 7. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V). For test circuit see Figure 12.

Symbol	Parameter	Conditions		–40 °C to +85 °C			Unit
				Min	Typ[1]	Max	
t_{pd}	propagation delay	Dn to Qn; see Figure 8	[2]				
		V_{CC} = 1.65 V to 1.95 V		1.0	2.5	5.4	ns
		V_{CC} = 2.3 V to 2.7 V		1.0	2.0	3.5	ns
		V_{CC} = 2.7 V		1.0	2.3	3.6	ns
		V_{CC} = 3.0 V to 3.6 V		1.0	2.2	3.3	ns
		LE to Qn; see Figure 9					
		V_{CC} = 1.65 V to 1.95 V		1.0	2.8	6.0	ns
		V_{CC} = 2.3 V to 2.7 V		1.0	2.1	3.8	ns
		V_{CC} = 2.7 V		1.0	2.4	3.7	ns
		V_{CC} = 3.0 V to 3.6 V		1.0	2.3	3.3	ns
t_{en}	enable time	$\overline{OE}$ to Qn; see Figure 10	[2]				
		V_{CC} = 1.65 V to 1.95 V		1.5	3.0	6.4	ns
		V_{CC} = 2.3 V to 2.7 V		1.0	2.4	4.5	ns
		V_{CC} = 2.7 V		1.5	3.0	4.6	ns
		V_{CC} = 3.0 V to 3.6 V		1.0	2.3	4.0	ns
t_{dis}	disable time	$\overline{OE}$ to Qn; see Figure 10	[2]				
		V_{CC} = 1.65 V to 1.95 V		1.5	3.4	7.0	ns
		V_{CC} = 2.3 V to 2.7 V		1.0	2.2	4.4	ns
		V_{CC} = 2.7 V		1.5	2.8	4.4	ns
		V_{CC} = 3.0 V to 3.6 V		1.0	2.7	4.4	ns

Table 7. Dynamic characteristics *…continued*

Voltages are referenced to GND (ground = 0 V). For test circuit see Figure 12.

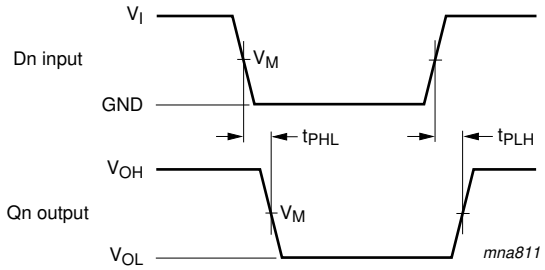
Symbol	Parameter	Conditions	–40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
t_W	pulse width	LE pulse width HIGH; see Figure 9				
		V_{CC} = 1.65 V to 1.95 V	3.8	-	-	ns
		V_{CC} = 2.3 V to 2.7 V	3.3	-	-	ns
		V_{CC} = 2.7 V	3.3	-	-	ns
		V_{CC} = 3.0 V to 3.6 V	3.3	-	-	ns
t_{su}	set-up time	Dn to LE; see Figure 11				
		V_{CC} = 1.65 V to 1.95 V	0.8	-	-	ns
		V_{CC} = 2.3 V to 2.7 V	0.8	-	-	ns
		V_{CC} = 2.7 V	0.8	-	-	ns
		V_{CC} = 3.0 V to 3.6 V	0.8	-	-	ns
t_h	hold time	Dn to LE; see Figure 11				
		V_{CC} = 1.65 V to 1.95 V	0.8	-	-	ns
		V_{CC} = 2.3 V to 2.7 V	0.8	-	-	ns
		V_{CC} = 2.7 V	0.8	-	-	ns
		V_{CC} = 3.0 V to 3.6 V	0.7	-	-	ns
C_{PD}	power dissipation capacitance	per latch; V_I = GND to V_{CC}; V_{CC} = 3.3 V [3]				
		outputs HIGH or LOW state	-	37	-	pF
		outputs 3-state	-	7	-	pF

[1] Typical values are measured at T_{amb} = 25 °C

[2] t_{pd} is the same as t_{PHL} and t_{PLH}.
t_{en} is the same as t_{PZH} and t_{PZL}.
t_{dis} is the same as t_{PHZ} and t_{PLZ}.

[3] C_{PD} is used to determine the dynamic power dissipation (P_D in µW).
$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o)$ where:
f_i = input frequency in MHz; f_o = output frequency in MHz
C_L = output load capacitance in pF
V_{CC} = supply voltage in Volts
N = number of inputs switching
$\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs

11. Waveforms



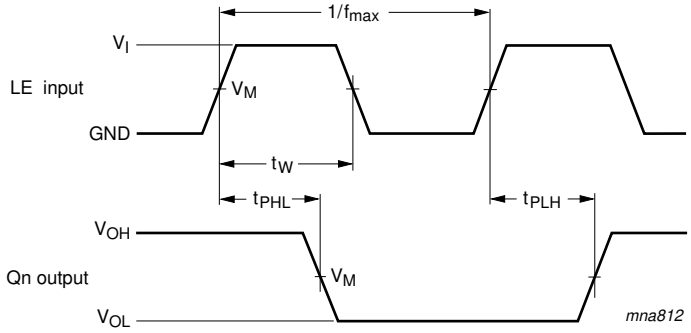
Measurement points are given in Table 8.

V_{OL} and V_{OH} are the typical output voltage levels that occur with the output load.

Fig 8. Input Dn to output Qn propagation delay times

Table 8. Measurement points

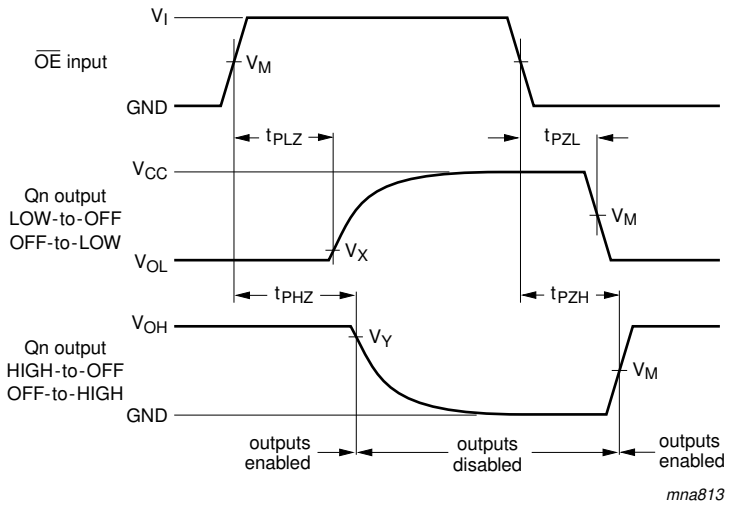
Supply voltage V_{CC}	V_M	Output	
		V_X	V_Y
1.65 V to 1.95 V	$0.5V_{CC}$	V_{OL} + 0.15 V	V_{OH} – 0.15 V
2.3 V to 2.7 V	$0.5V_{CC}$	V_{OL} + 0.15 V	V_{OH} – 0.15 V
2.7 V	1.5 V	V_{OL} + 0.3 V	V_{OH} – 0.3 V
3.0 V to 3.6 V	1.5 V	V_{OL} + 0.3 V	V_{OH} – 0.3 V



Measurement points are given in Table 8.

V_{OL} and V_{OH} are the typical output voltage levels that occur with the output load.

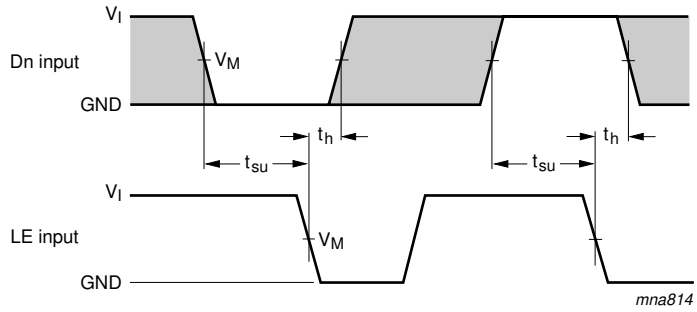
Fig 9. Latch enable (LE) pulse width and latch enable input to output (Qn) propagation delays



Measurement points are given in Table 8.

V_{OL} and V_{OH} are the typical output voltage levels that occur with the output load.

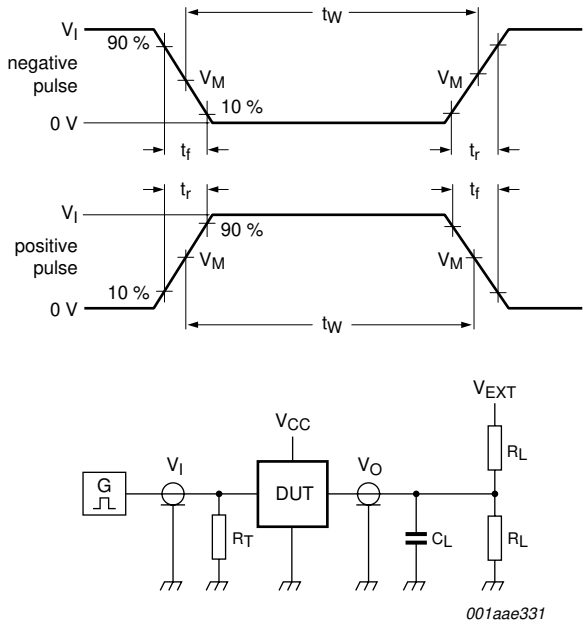
Fig 10. Enable and disable times



Measurement points are given in Table 8.

The shaded areas indicate when the input is permitted to change for predicable output performance.

Fig 11. The data set-up and hold times for Dn input to LE input



Test data is given in Table 9.

Definitions for test circuit:

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

R_T = Termination resistance should be equal to output impedance Z_o of the pulse generator.

V_{EXT} = External voltage for measuring switching times.

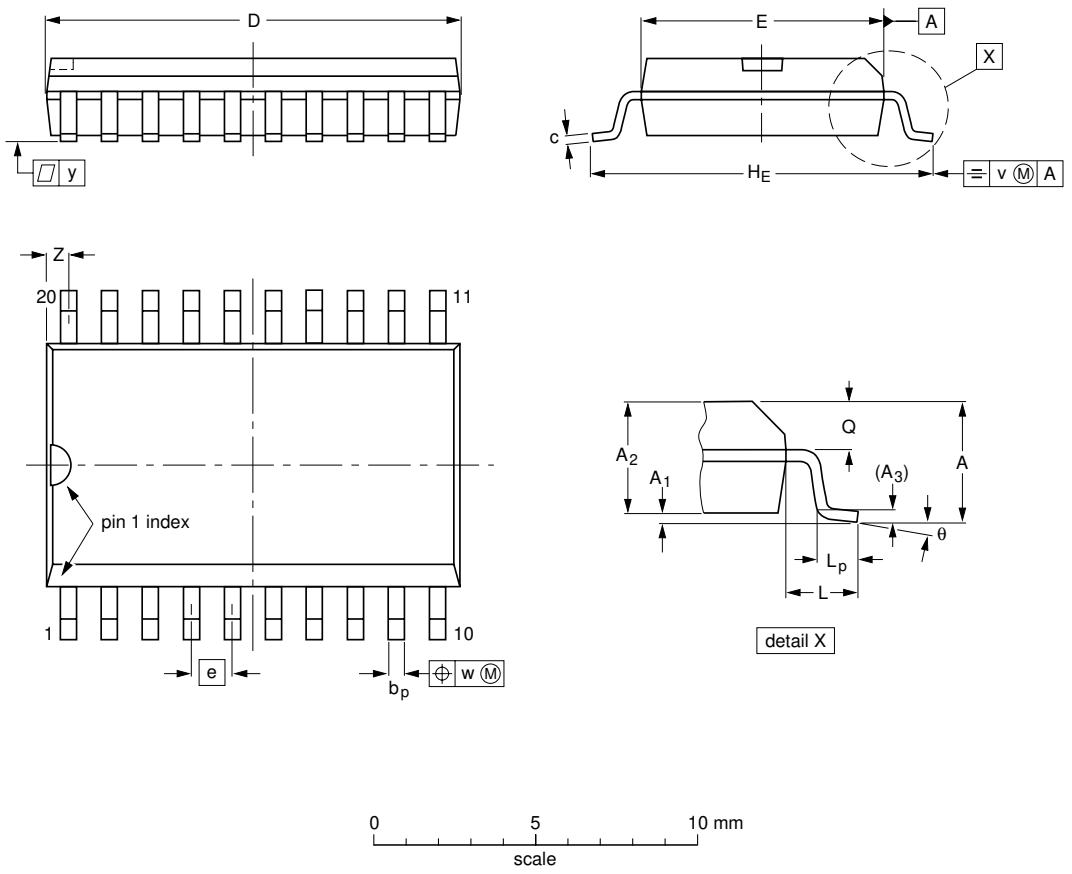
Fig 12. Test circuitry for switching times

Table 9. Test data

Supply voltage	Input		Load		V_{EXT}		
	V_I	t_r, t_f	C_L	R_L	t_{PLH}, t_{PHL}	t_{PLZ}, t_{PZL}	t_{PHZ}, t_{PZH}
1.65 V to 1.95 V	V_{CC}	≤ 2.0 ns	30 pF	1 kΩ	open	$2V_{CC}$	GND
2.3 V to 2.7 V	V_{CC}	≤ 2.0 ns	30 pF	500 Ω	open	$2V_{CC}$	GND
2.7 V	2.7 V	≤ 2.5 ns	50 pF	500 Ω	open	6 V	GND
3.0 V to 3.6 V	2.7 V	≤ 2.5 ns	50 pF	500 Ω	open	6 V	GND

12. Package outline

SO20: plastic small outline package; 20 leads; body width 7.5 mm **SOT163-1**



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A_1	A_2	A_3	b_p	c	$D^{(1)}$	$E^{(1)}$	e	H_E	L	L_p	Q	v	w	y	$Z^{(1)}$	θ
mm	2.65	0.3 0.1	2.45 2.25	0.25	0.49 0.36	0.32 0.23	13.0 12.6	7.6 7.4	1.27	10.65 10.00	1.4	1.1 0.4	1.1 1.0	0.25	0.25	0.1	0.9 0.4	8° 0°
inches	0.1	0.012 0.004	0.096 0.089	0.01	0.019 0.014	0.013 0.009	0.51 0.49	0.30 0.29	0.05	0.419 0.394	0.055	0.043 0.016	0.043 0.039	0.01	0.01	0.004	0.035 0.016	

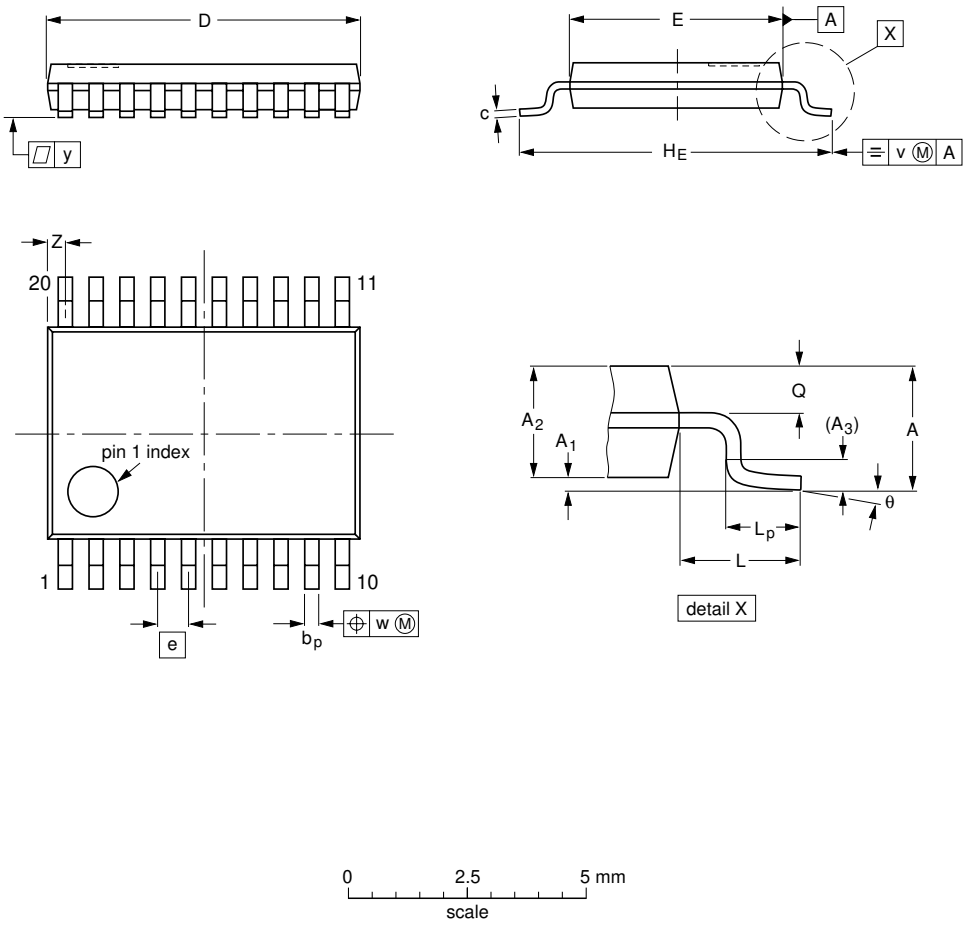
Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT163-1	075E04	MS-013				~~99-12-27~~ 03-02-19

Fig 13. Package outline SOT163-1 (SO20)

TSSOP20: plastic thin shrink small outline package; 20 leads; body width 4.4 mm **SOT360-1**



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A_1	A_2	A_3	b_p	c	D (1)	E (2)	e	H_E	L	L_p	Q	v	w	y	Z (1)	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	6.6 6.4	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.5 0.2	8° 0°

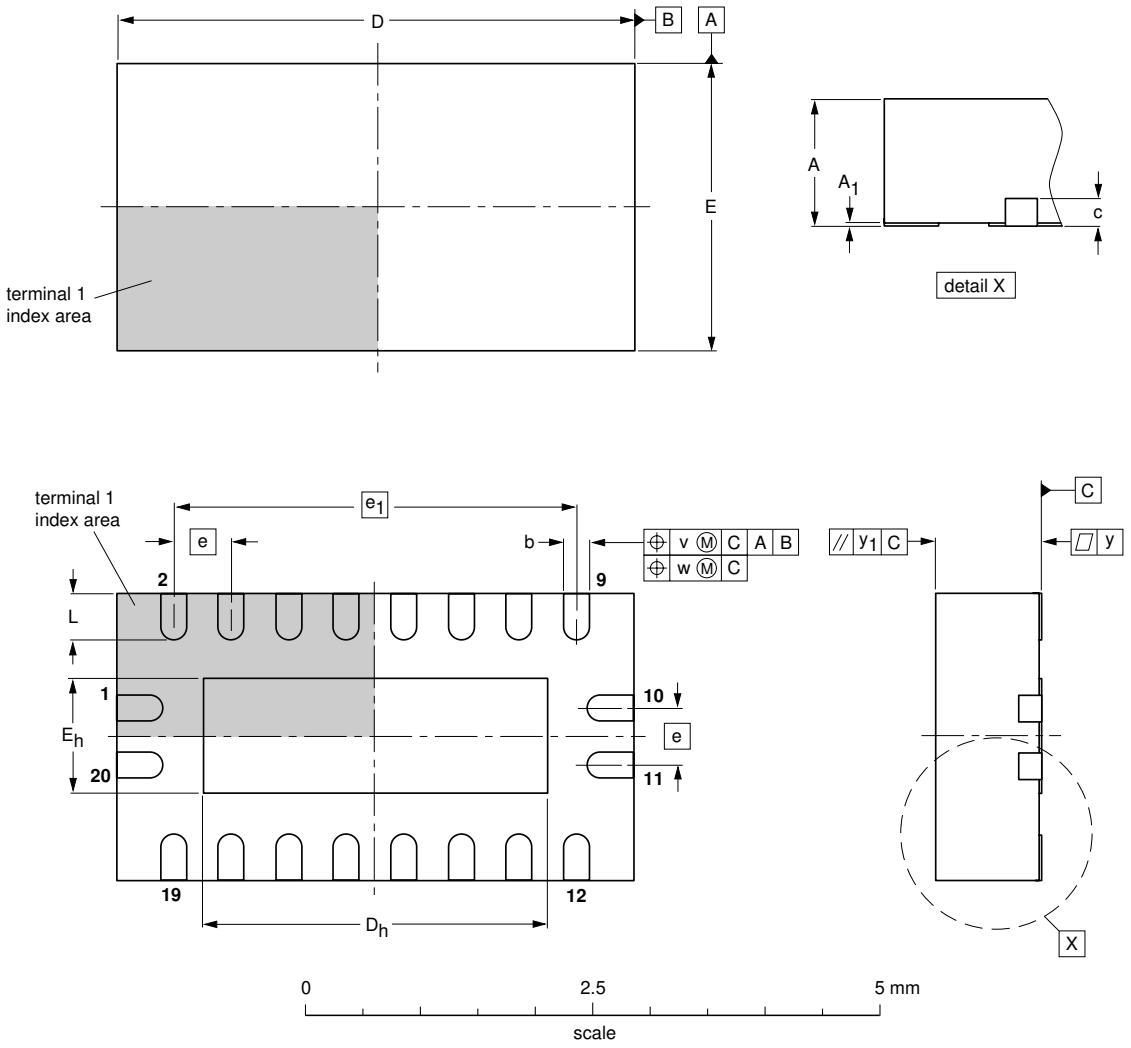
Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT360-1		MO-153				~~99-12-27~~ 03-02-19

Fig 14. Package outline SOT360-1 (TSSOP20)

DHVQFN20: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body 2.5 x 4.5 x 0.85 mm **SOT764-1**



DIMENSIONS (mm are the original dimensions)

UNIT	$A^{(1)}$ max.	A_1	b	c	$D^{(1)}$	D_h	$E^{(1)}$	E_h	e	e_1	L	v	w	y	y_1
mm	1	0.05 0.00	0.30 0.18	0.2	4.6 4.4	3.15 2.85	2.6 2.4	1.15 0.85	0.5	3.5	0.5 0.3	0.1	0.05	0.05	0.1

Note

1. Plastic or metal protrusions of 0.075 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT764-1	- - -	MO-241	- - -			~~02-10-17~~ 03-01-27

Fig 15. Package outline SOT764-1 (DHVQFN20)

13. Abbreviations

Table 10. Abbreviations

Acronym	Description
CDM	Charged Device Model
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

14. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ALVC573_3	20071026	Product data sheet	-	74ALVC573_2
Modifications:	• The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. • Legal texts have been adapted to the new company name where appropriate. • Section 3: DHVQFN20 package added. • Section 8: derating values added for DHVQFN20 package. • Section 12: outline drawing added for DHVQFN20 package.			
74ALVC573_2	20030625	Product specification	-	74ALVC573_1
74ALVC573_1	20020301	Product specification	-	-

15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

15.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

15.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of a NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

15.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

16. Contact information

For additional information, please visit: **http://www.nxp.com**

For sales office addresses, send an email to: **salesaddresses@nxp.com**

17. Contents

For more information, please visit: http://www.nxp.com
For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 26 October 2007
Document identifier: 74ALVC573_3